

Lonten N-channel 500V, 25A Power MOSFET

Description

The Power MOSFET is fabricated using the advanced planer **VDMOS** technology. The resulting device has low conduction resistance, superior switching performance and high avalanche energy.

Features

- ◆ Low $R_{DS(on)}$
- ◆ Low gate charge (typ. $Q_g = 78 \text{ nC}$)
- ◆ 100% UIS tested
- ◆ RoHS compliant

Applications

- ◆ Power factor correction.
- ◆ Switched mode power supplies.
- ◆ LED driver.

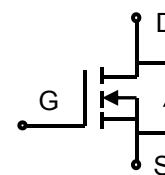
Product Summary

V_{DSS}	500V
I_D	25A
$R_{DS(on),max}$	0.2Ω
$Q_{g,typ}$	78 nC

Pin Configuration



TO-220F



N-Channel MOSFET

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	500	V
Continuous drain current ($T_c = 25^\circ\text{C}$)	I_D	25	A
($T_c = 100^\circ\text{C}$)		16	A
Pulsed drain current ¹⁾	I_{DM}	100	A
Gate-Source voltage	V_{GSS}	± 30	V
Avalanche energy, single pulse ²⁾	E_{AS}	1280	mJ
Power Dissipation ($T_c = 25^\circ\text{C}$)	P_D	40	W
Operating junction and storage temperature range	T_J, T_{STG}	-55 to +150	°C
Continuous diode forward current	I_S	25	A
Diode pulse current	$I_{S,pulse}$	100	A

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, Junction-to-case	$R_{\theta JC}$	3.1	°C/W
Thermal resistance, Junction-to-ambient ³⁾	$R_{\theta JA}$	65	°C/W

Package Marking and Ordering Information

Device	Device Package	Marking	Units/Tube
LND25N50W	TO-220F	LND25N50W	50

Electrical Characteristics
 $T_c = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV_{DSS}	$V_{\text{GS}}=0 \text{ V}, I_{\text{D}}=0.25 \text{ mA}$	500	-	-	V
Gate threshold voltage	$V_{\text{GS(th)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=0.25 \text{ mA}$	2	-	4	V
Drain cut-off current	I_{DSS}	$V_{\text{DS}}=500 \text{ V}, V_{\text{GS}}=0 \text{ V},$ $T_j = 25^\circ\text{C}$ $T_j = 150^\circ\text{C}$	-	-	1 100	μA
Gate leakage current, Forward	I_{GSSF}	$V_{\text{GS}}=30 \text{ V}, V_{\text{DS}}=0 \text{ V}$	-	-	100	nA
Gate leakage current, Reverse	I_{GSSR}	$V_{\text{GS}}=-30 \text{ V}, V_{\text{DS}}=0 \text{ V}$	-	-	-100	nA
Drain-source on-state resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}}=10 \text{ V}, I_{\text{D}}=12.5 \text{ A}, T_j=25^\circ\text{C}$	-	0.16	0.2	Ω
Gate resistance	R_g	$V_{\text{GS}}=0 \text{ V}, V_{\text{DS}}=0 \text{ V}, f=1 \text{ MHz}$	-	1.7	-	Ω
Dynamic characteristics						
Input capacitance	C_{iss}	$V_{\text{DS}} = 25 \text{ V}, V_{\text{GS}} = 0 \text{ V},$ $f = 1 \text{ MHz}$	-	4112	-	pF
Output capacitance	C_{oss}		-	369	-	
Reverse transfer capacitance	C_{rss}		-	20	-	
Turn-on delay time	$t_{\text{d(on)}}$	$V_{\text{DD}} = 250 \text{ V}, I_{\text{D}} = 25 \text{ A}$ $R_G = 10 \Omega, V_{\text{GS}} = 15 \text{ V}$	-	20.7	-	ns
Rise time	t_r		-	20	-	
Turn-off delay time	$t_{\text{d(off)}}$		-	149	-	
Fall time	t_f		-	21.2	-	
Gate charge characteristics						
Gate to source charge	Q_{gs}	$V_{\text{DD}}=400 \text{ V}, I_{\text{D}}=25 \text{ A},$ $V_{\text{GS}}=0 \text{ to } 10 \text{ V}$	-	19	-	nC
Gate to drain charge	Q_{gd}		-	18.2	-	
Gate charge total	Q_g		-	78	-	
Gate plateau voltage	V_{plateau}		-	5	-	V
Reverse diode characteristics						
Diode forward voltage	V_{SD}	$V_{\text{GS}}=0 \text{ V}, I_{\text{F}}=25 \text{ A}$	-	-	1.3	V
Reverse recovery time	t_{rr}	$V_R=400 \text{ V}, I_{\text{F}}=25 \text{ A},$ $dI_{\text{F}}/dt=100 \text{ A}/\mu\text{s}$	-	372	-	ns
Reverse recovery charge	Q_{rr}		-	4947	-	μC
Peak reverse recovery current	I_{rrm}		-	26.6	-	A

Notes:

1. Pulse width limited by maximum junction temperature.
2. $V_{\text{DD}}=60 \text{ V}, L=10 \text{ mH}, I_{\text{AS}} = 16 \text{ A}$, Starting $T_j = 25^\circ\text{C}$.
- 3: The value of R_{thJA} is measured by placing the device in a still air box which is one cubic foot.

Electrical Characteristics Diagrams

Figure 1. Typical Output Characteristics

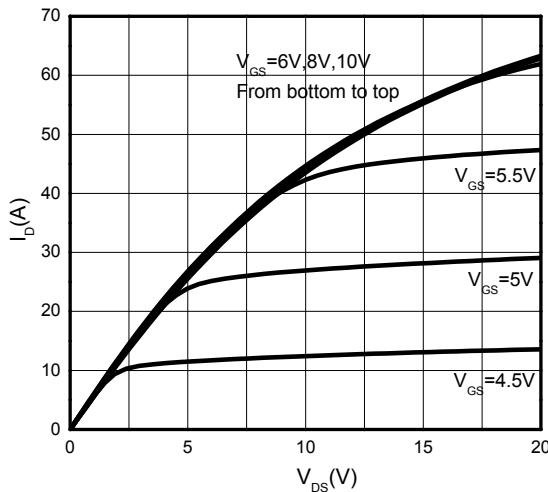


Figure 2. Transfer Characteristics

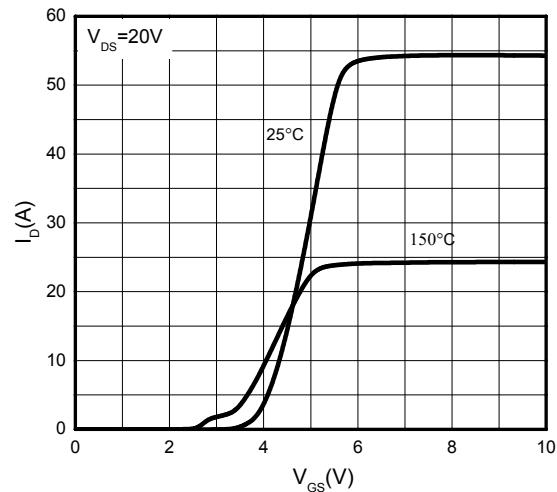


Figure 3. On-Resistance vs. Drain Current

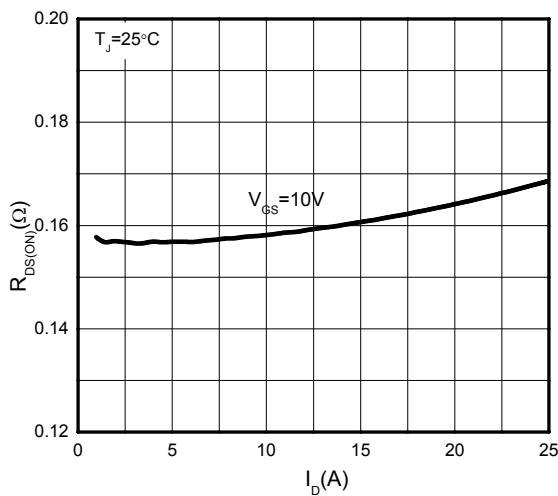


Figure 4. On-Resistance vs. Temperature

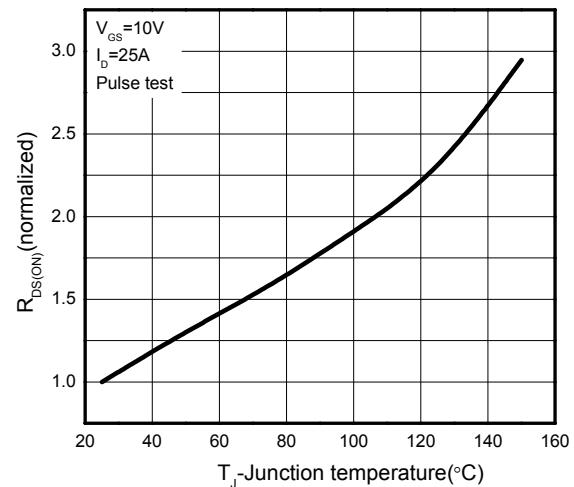


Figure 5. Breakdown Voltage vs. Temperature

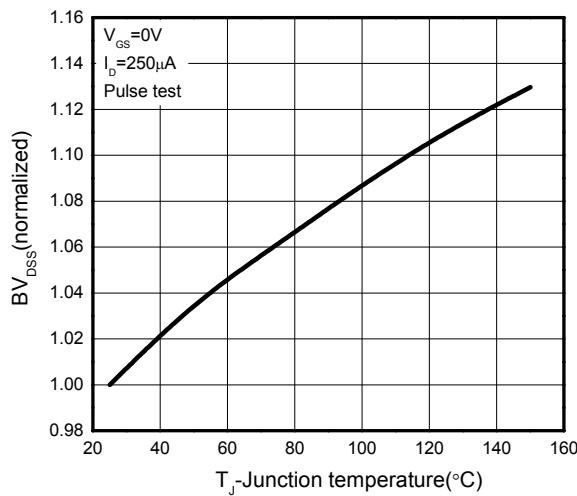


Figure 6. Threshold Voltage vs. Temperature

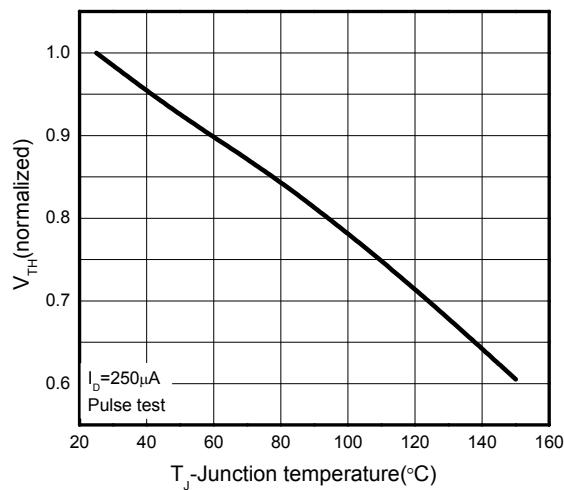


Figure 7.Rds(on) vs. Gate Voltage

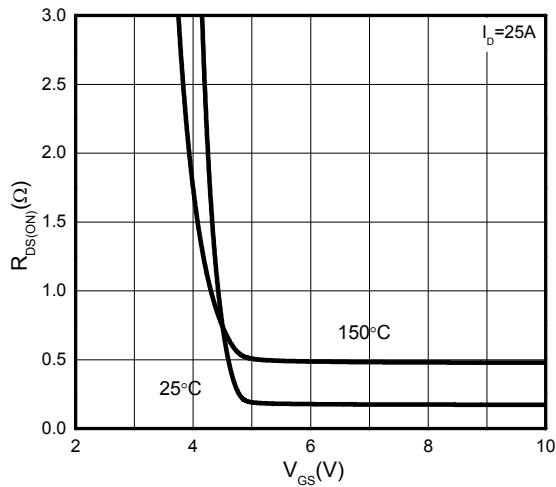


Figure 9. Capacitance Characteristics

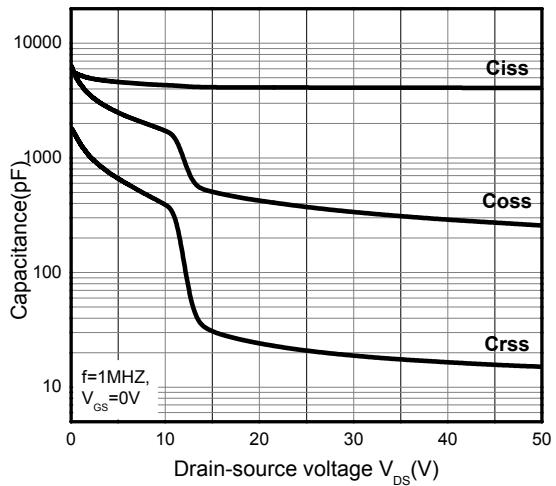


Figure 11. Continuous Drain Current vs. Temperature

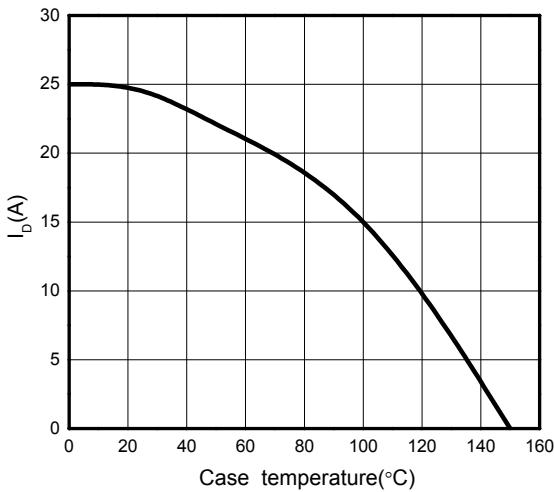


Figure 8.Body-Diode Characteristics

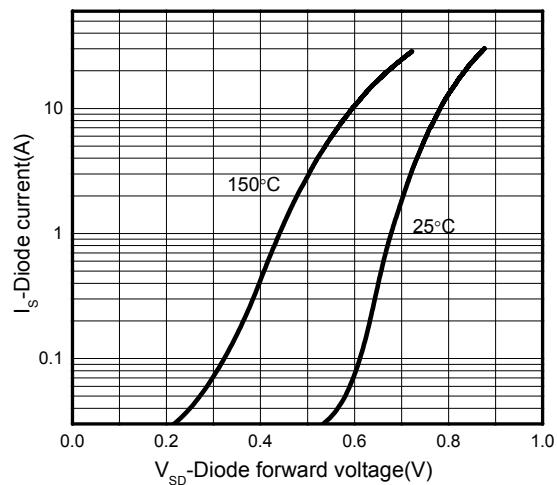


Figure 10. Gate Charge Characteristics

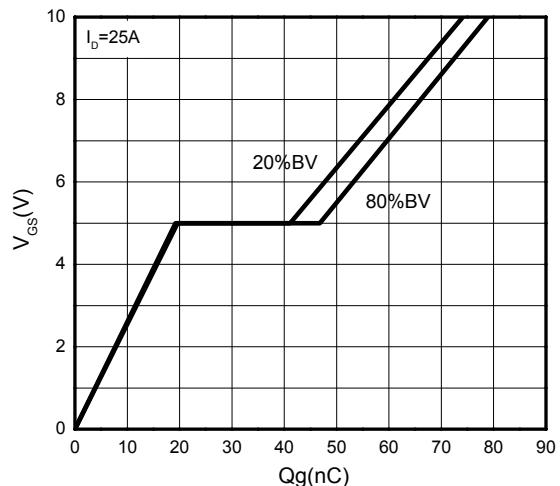


Figure 12. Power Dissipation vs. Temperature

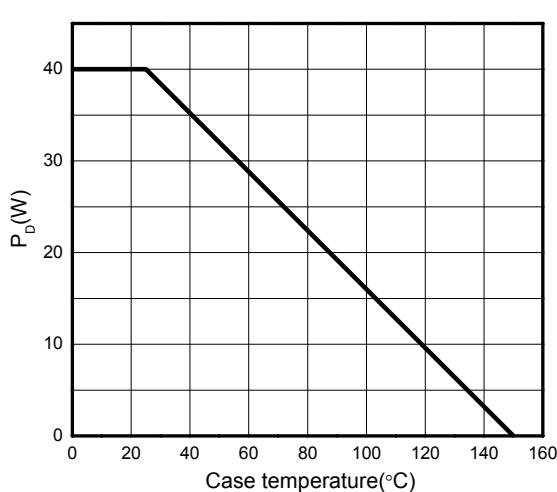


Figure 13: Safe Operating Area

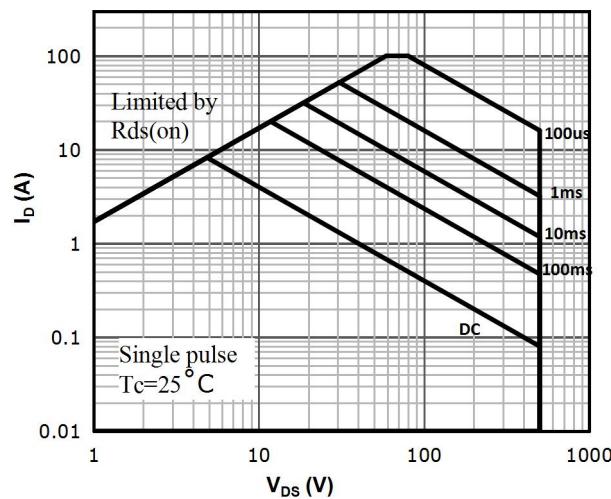
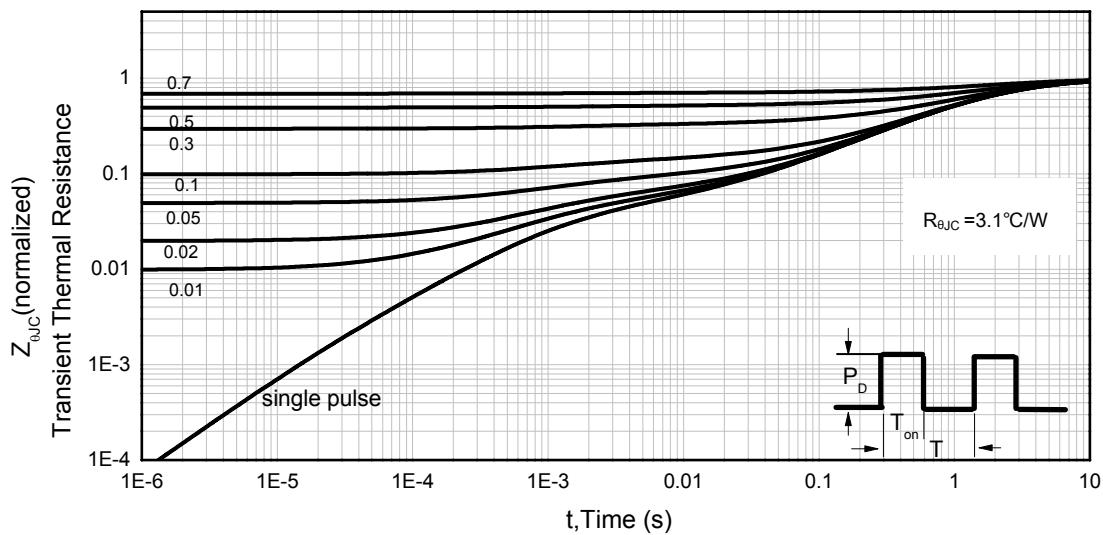
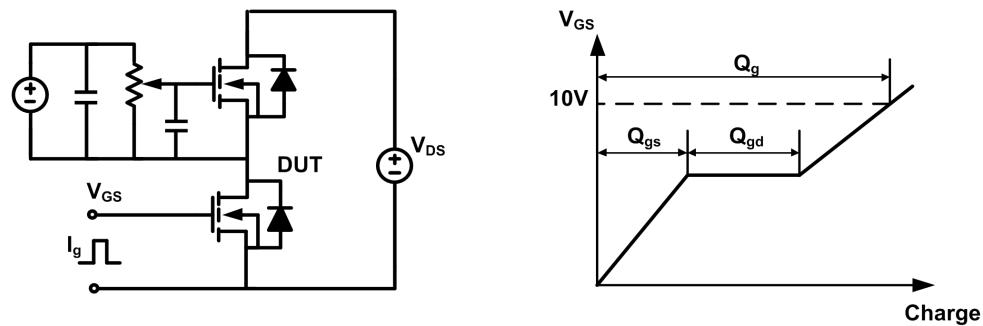


Figure 14. Transient Thermal Impedance, Junction to Case

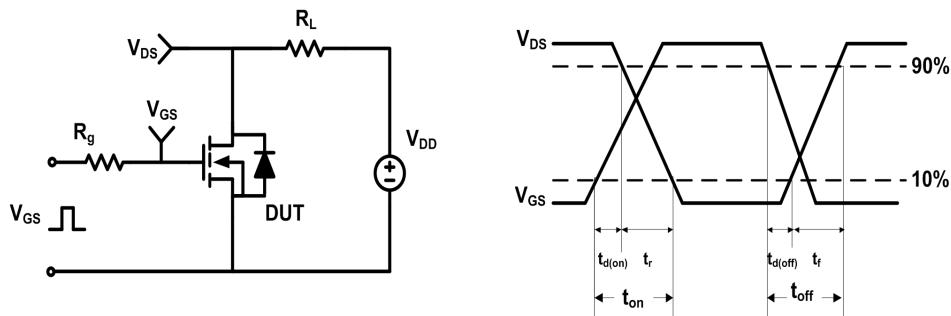


Test Circuit & Waveforms

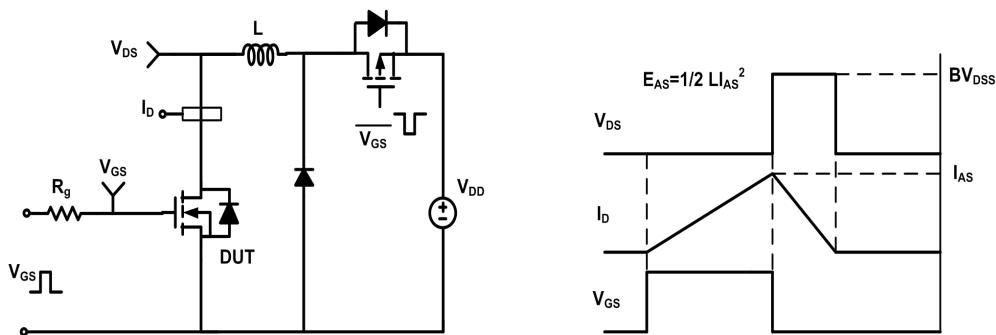
Gate Charge Test Circuit & Waveform



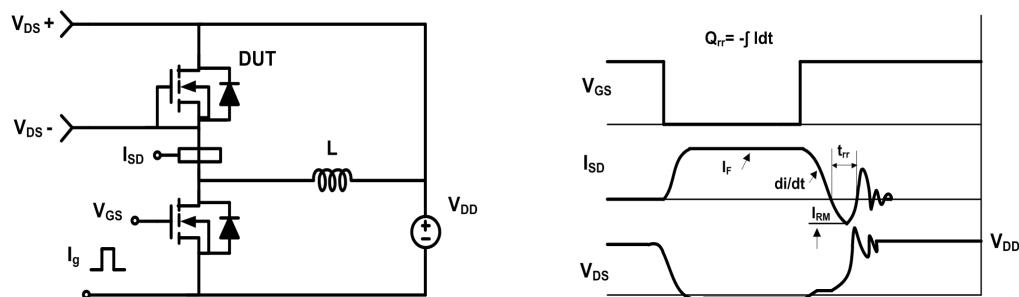
Resistive Switching Test Circuit & Waveform



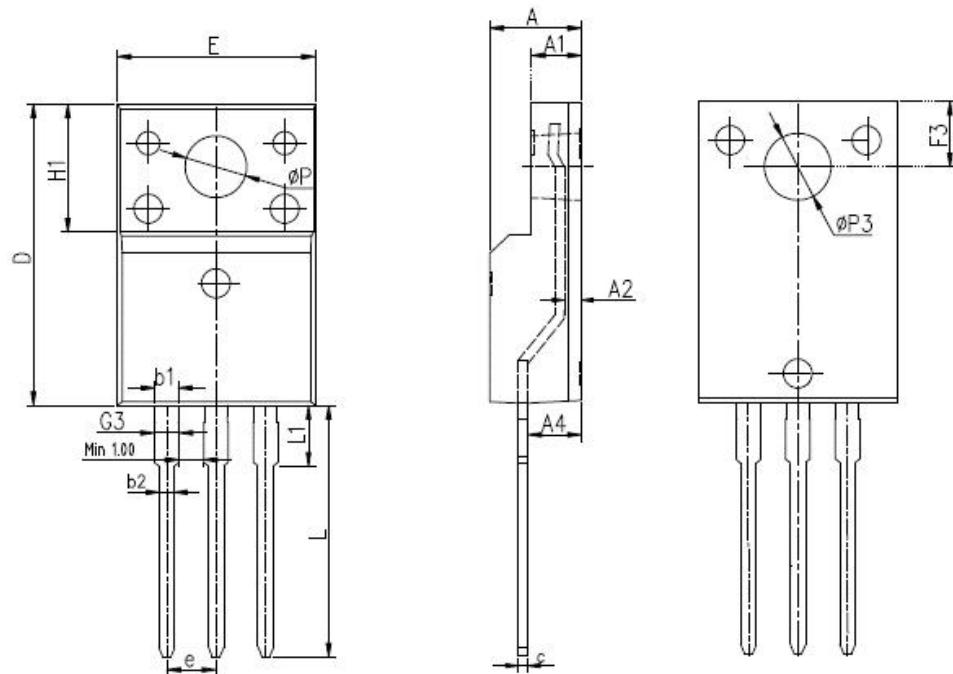
Unclamped Inductive Switching (UIS) Test Circuit & Waveform



Diode Recovery Test Circuit & Waveform



Mechanical Dimensions for TO-220F



DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES	
SYMBOL	MIN	MAX	MIN	MAX
A	4.4	4.9	0.173	0.193
A1	2.34	2.74	0.092	0.108
A2	0.3	0.7	0.012	0.028
A4	2.5	2.96	0.098	0.117
c	0.4	0.7	0.016	0.028
D	15.57	16.4	0.613	0.646
E	9.96	10.4	0.392	0.409
H1	6.48	6.95	0.255	0.274
e	2.54BSC		0.1BSC	
L	12.64	14.2	0.498	0.559
L1	2.88	3.6	0.113	0.142
ΦP	3	3.38	0.118	0.133
ΦP_3	3.15	3.65	0.124	0.144
F3	3.15	3.45	0.124	0.136
G3	1.15	1.58	0.045	0.062
b1	1.18	1.43	0.046	0.056
b2	0.7	1	0.028	0.039

Version Information

LND25N50W

Revision:2020-11-16 ,Rev 0.1

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